United States Patent [19]

Kitada et al.

[11] **Des. 271,568**

[45] ** **Nov. 29, 1983**

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[54] **ULTRASONIC WAVE THICKNESS METER**

[75] Inventors: **Toyohiko Kitada**, Sagamihara; **Minoru Tamura**, Chigasaki; **Takanori Arioka**, Tokyo, all of Japan

[73] Assignee: **Tokyo Keiki Company Limited**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **248,545**

[22] Filed: **Mar. 27, 1981**

[30] **Foreign Application Priority Data**

Oct. 31, 1980 [JP] Japan 55-45358

[51] **Int. Cl.** .... **D10—04**

[52] **U.S. Cl.** **D10/46**

[58] **Field of Search** .... D10/46–47, D10/57, 75, 78, 102, 103, 61, 70; 73/597, 431, 432 R

[56] **References Cited**

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Attorney, Agent, or Firm—Fleit, Jacobson, Cohn & Price

[57] **CLAIM**

The ornamental design for an ultrasonic wave thickness meter, as shown and described.

DESCRIPTION

FIG. **1** is a front elevational view of an ultrasonic wave thickness meter showing our new design;

FIG. **2** is a rear view thereof;

FIG. **3** is a right side elevational view thereof;

FIG. **4** is a left side elevational view thereof;

FIG. **5** is a top plan view thereof; and

FIG. **6** is a bottom plan view thereof.

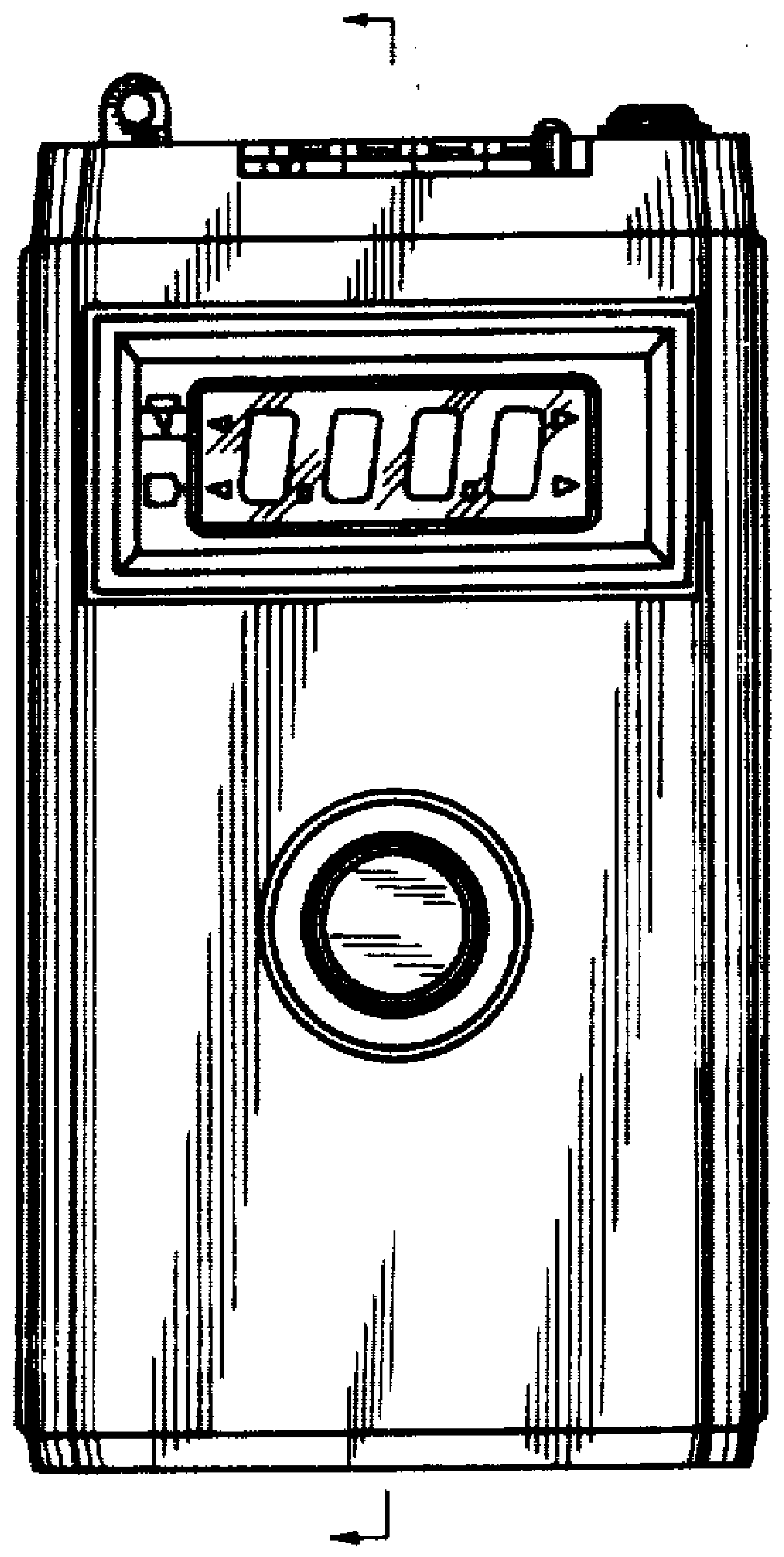

FIG. 1

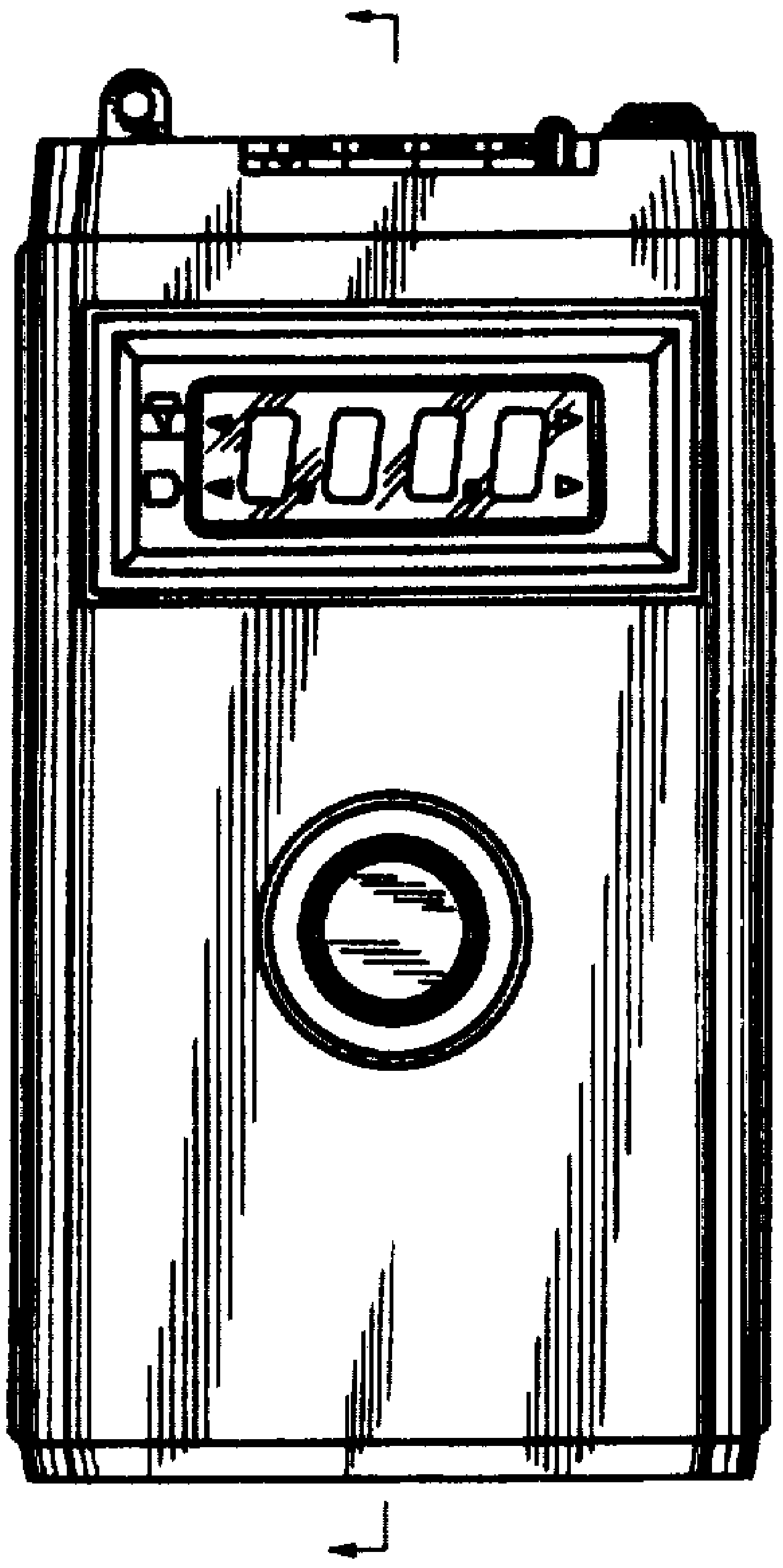

FIG. 2

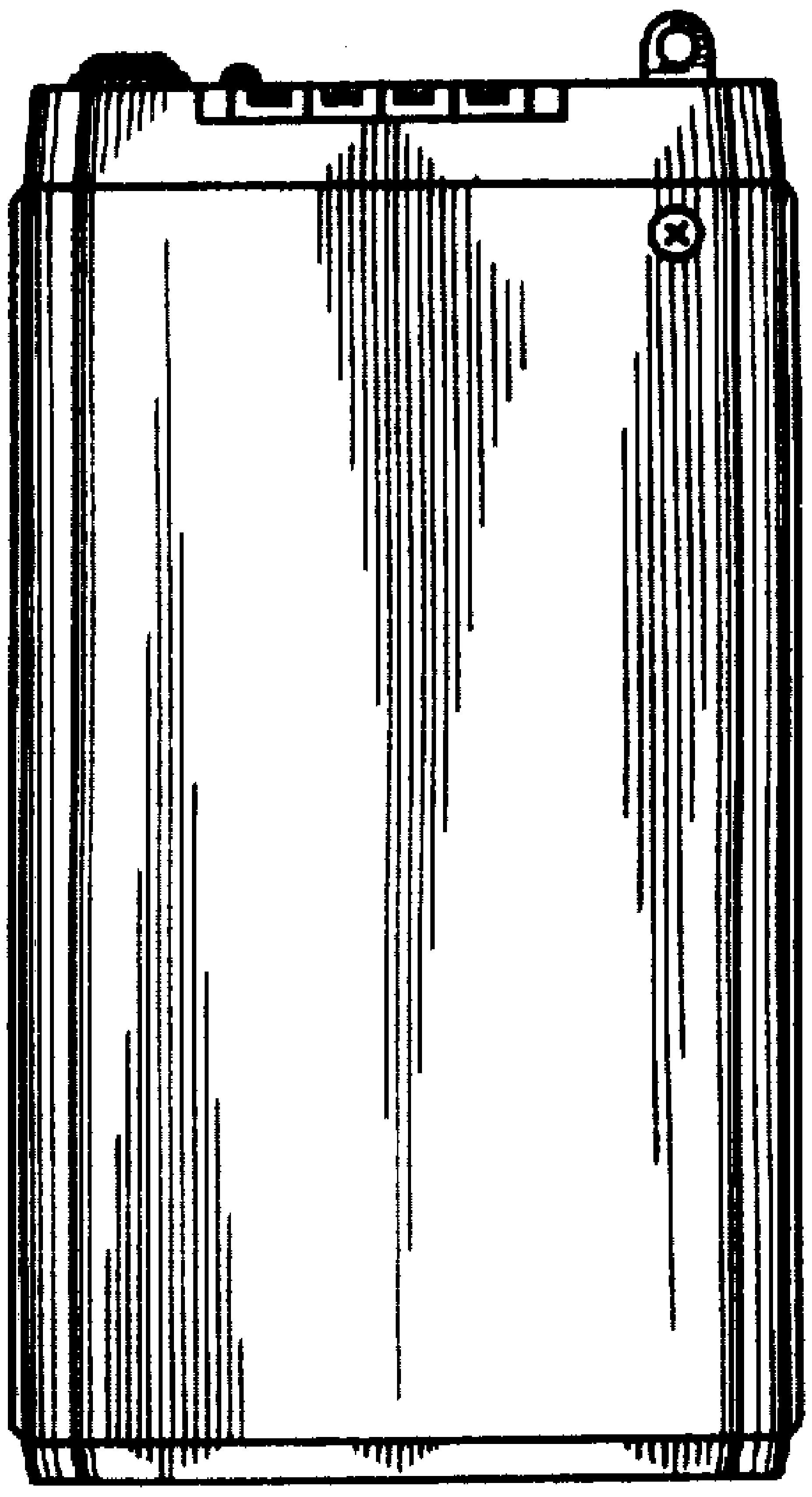

FIG. 3

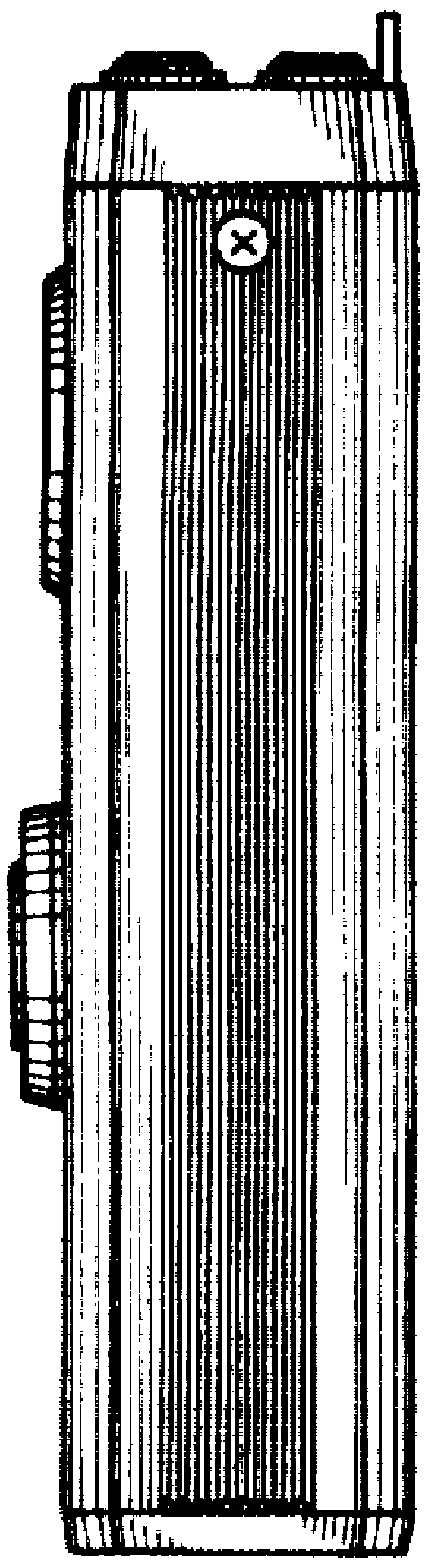

FIG. 4

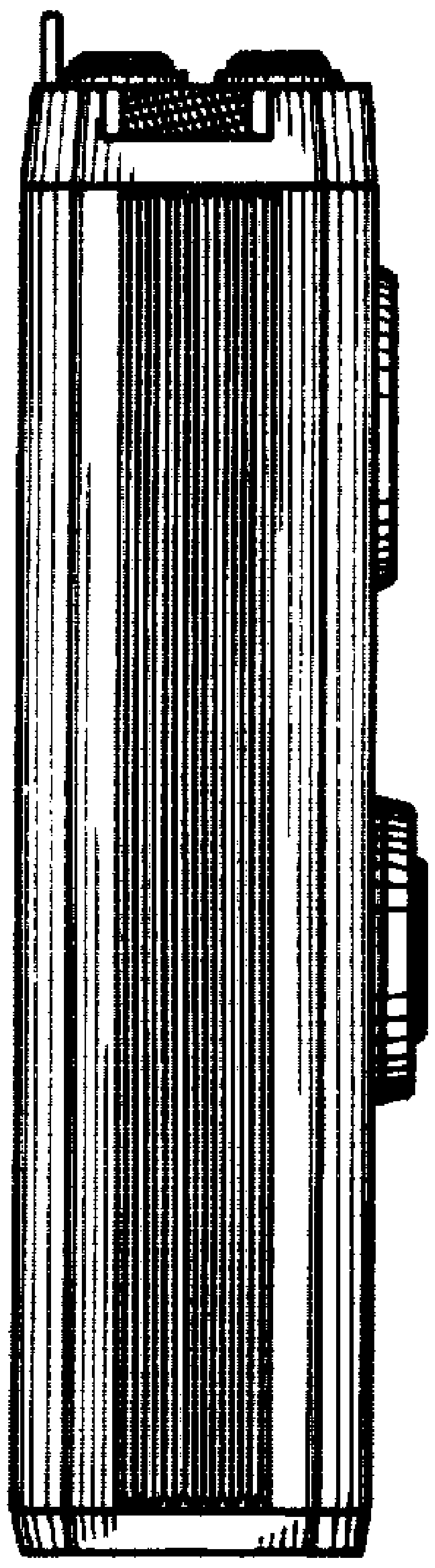

FIG. 5

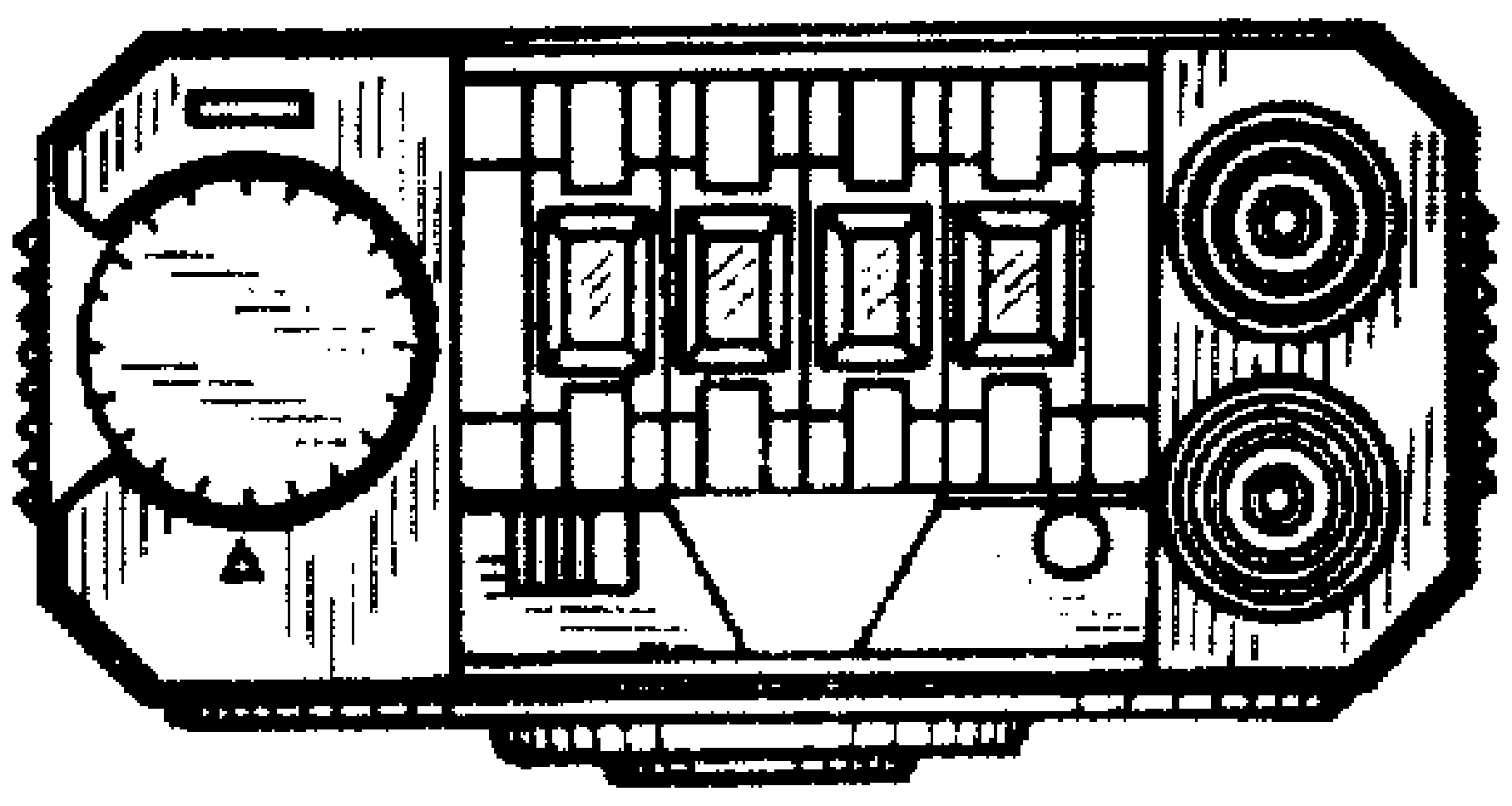

FIG. 6